

The "best" SEM Metrology Solution

ProSEM vs. InSPEC





Metrology Products



SEM Image Analysis & Metrology Software

- → Easy-to-use with existing tools
- → Mainly offline or with SEM remote
- → SEM auto: small area single field



Integrated SEM Metrology & Inspection Upgrade Kit

- → Sophisticated and comprehensive
- → Integrated solution for experts
- → Advanced multi-chip metrology jobs



ProSEM vs. InSPEC

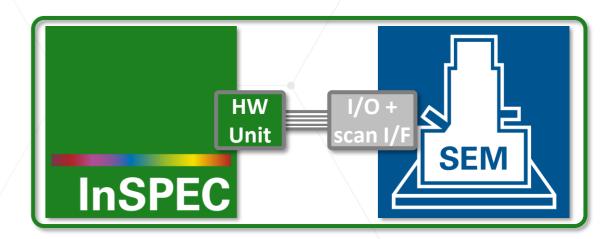


SW for SEM Image Analysis & Metrology

Easy-to-use Offline Software Package

Optional Automation via digital PC interface

Operation in conjunction with SEM SW



Upgrade Kit for a Metrology SEM

Integrated scanning, automation & metrology

Direct SEM control with hardware integration

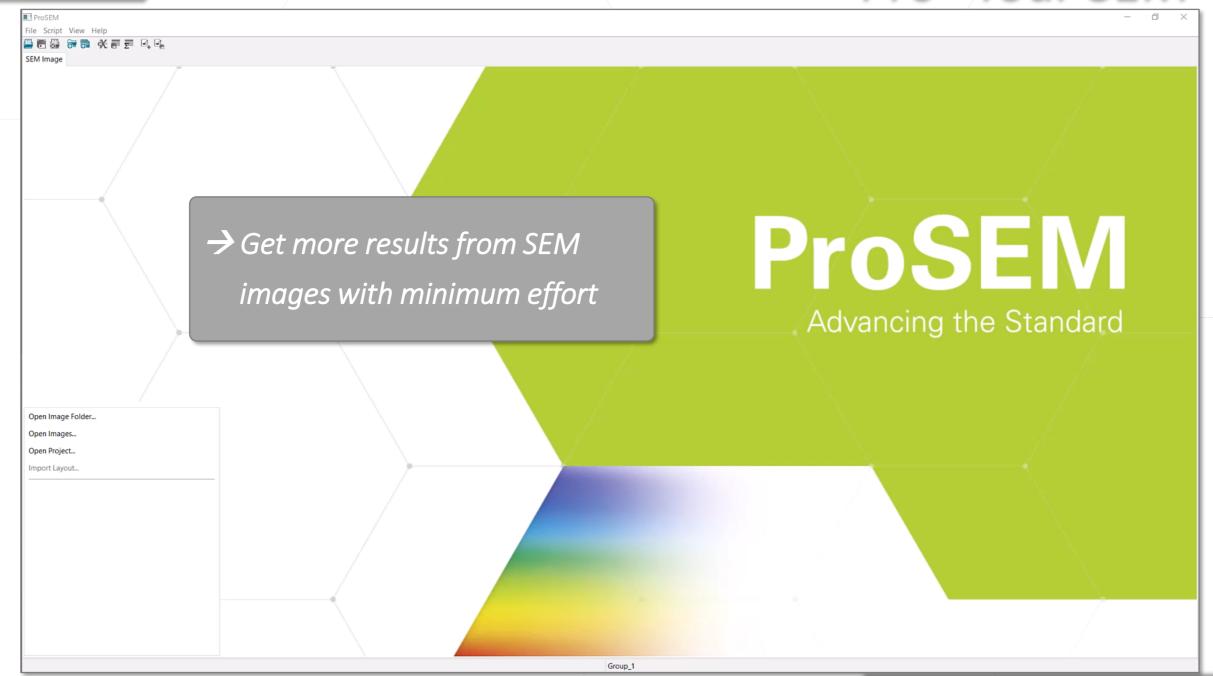
Multi-Chip jobs with hierarchical structure

Comprehensive full layout-based workflow

Expert metrology & data processing with "FLOW"



"Pro" Your SEM

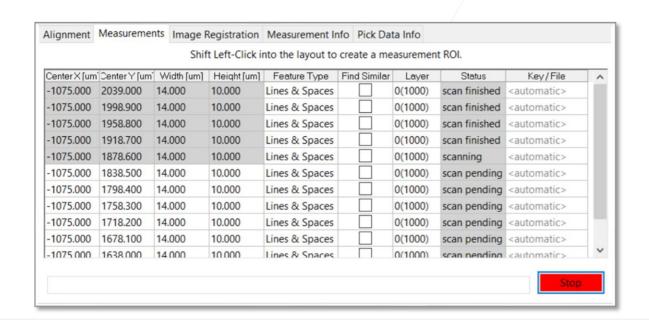


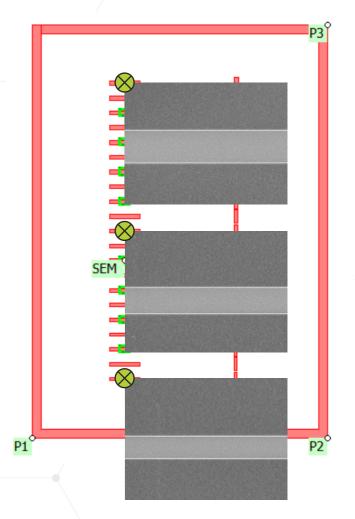


Step 1: Image Acquisition

Automated metrology

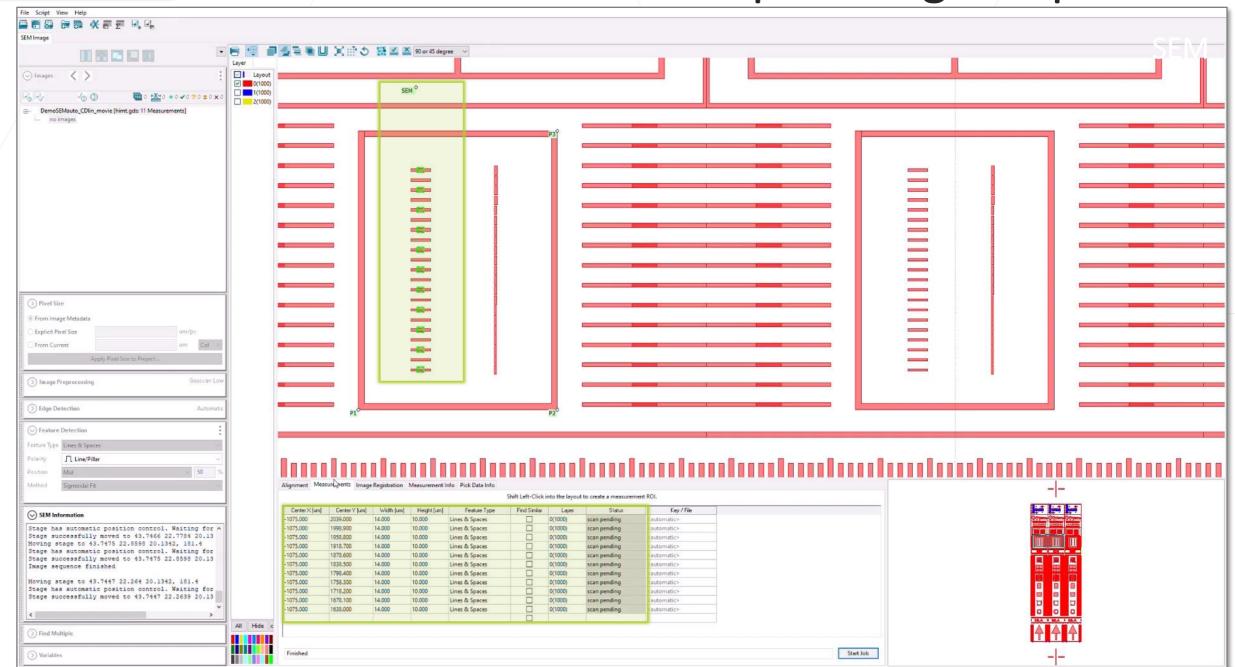
Drive SEM stage and acquire set of images







Step 1: Image Acquisition

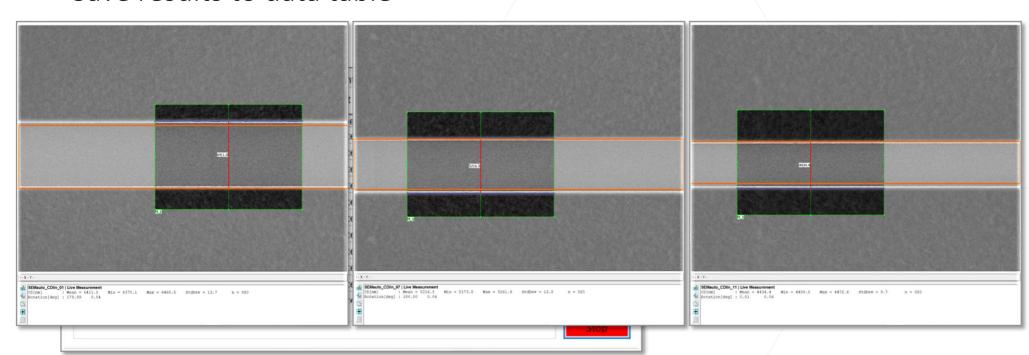


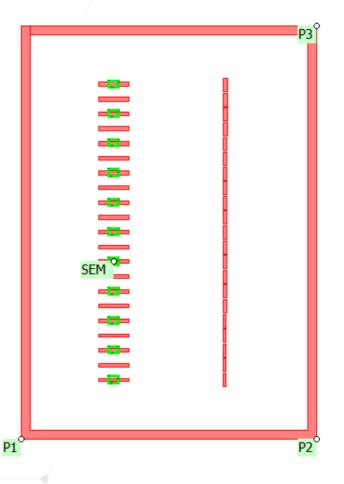


Step 2: Metrology

Automated metrology

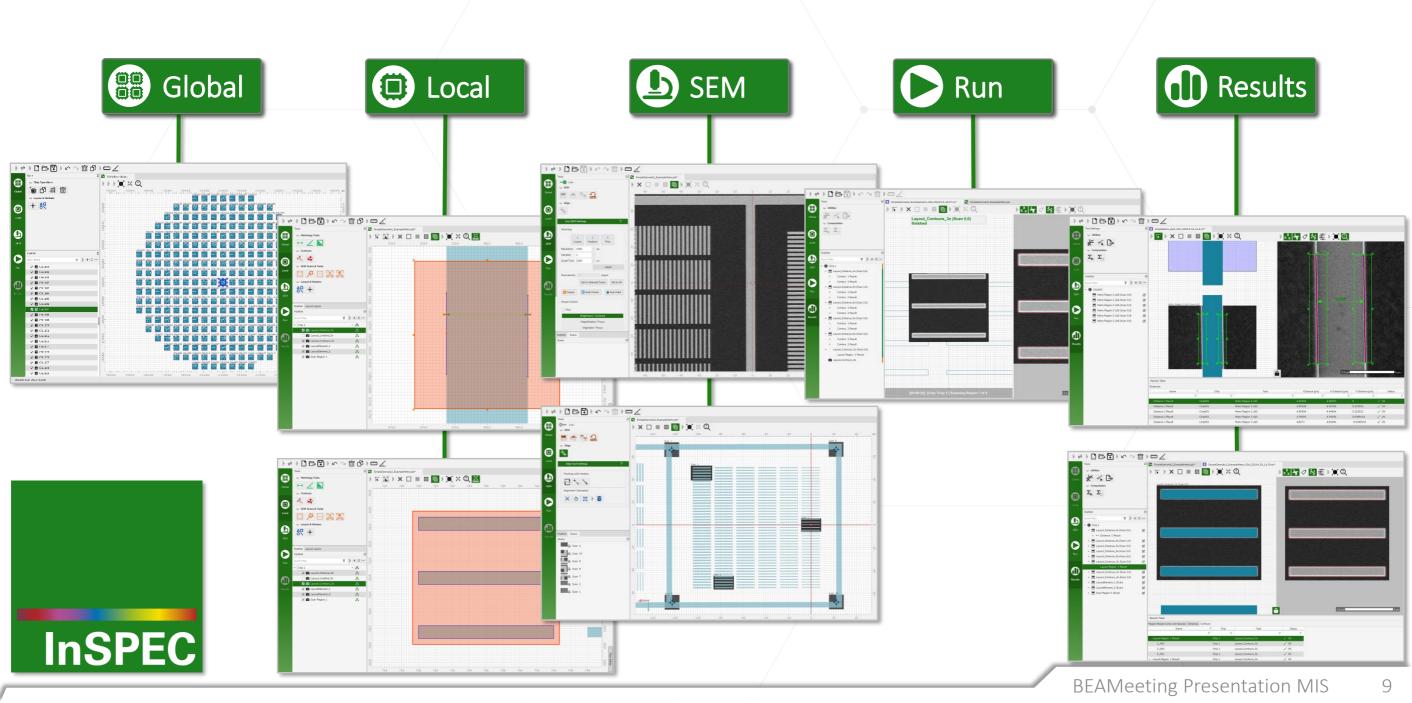
- Drive SEM stage and acquire set of images
- Load images with (local) alignment
- Apply pre-defined measurements automatically
- Save results to data table







Integrated Workflow along 5 Main Modes





Run the Metrology Job



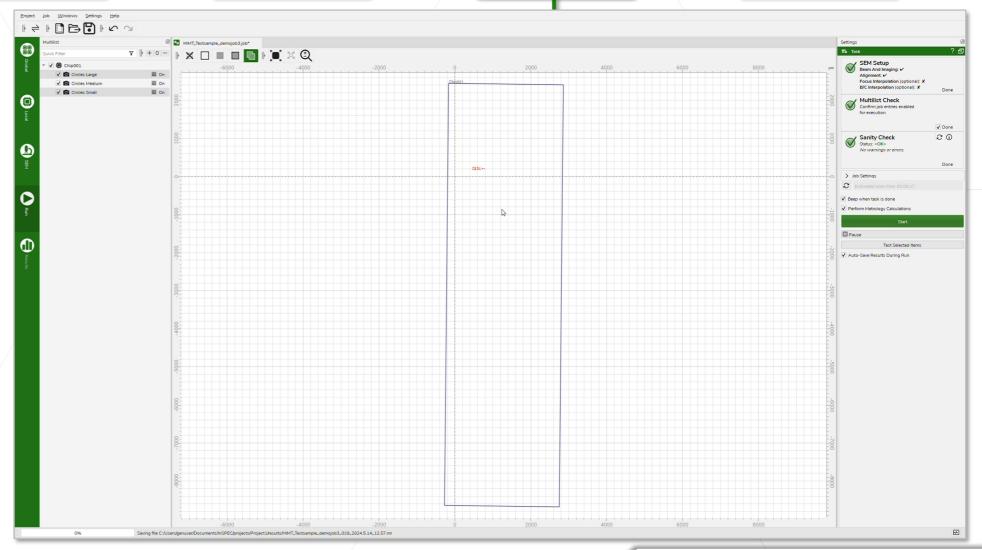








- Job execution
 - Job start and pause/ stop
 - Progress of job sequence
 - Live scans on layout
 - Parallel activities
 - Scanning
 - Corrections
 - Contour detection
 - Metrology
 - Data processing
 - Creates result file

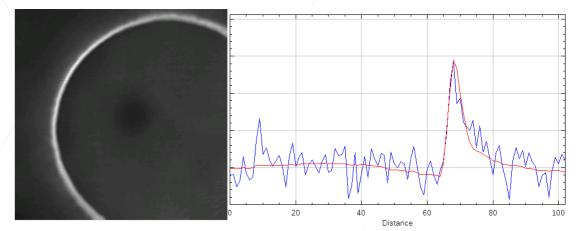


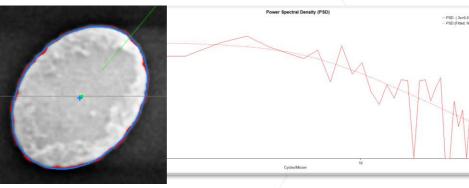


What's New ProSEM 3.5

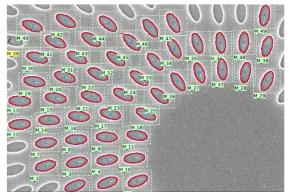
ProSEM 3.5 Key News

- General
 - New noise reduction filter "NL Means"
 - Image meta data for various SEM formats
 - Measurement data accuracy settings
- Feature Detection and Measurements
 - Slice measurement for edge and fit
 - Pixel calibration based on array vectors
 - Advanced Package: edge roughness for fitted 2D Shapes
 - Advanced Package: Find-Modified for rotated and scaled features
- Layout Integration/ SEM Automation
 - Display and project convenience
 - Automatic image naming
 - SEM interfaces for JEOL and Hitachi (more to come)











What's Next in MIS

- ProSEM 3.6 (for end of 2024)
 - User control for find-similar matching
 - Shape fitting with rounded corners
 - Additional SEM interfaces
- ProSEM new GUI (qt based)
 - Concept work started ("improved evolution")
 - Timing of release 4.0 linked to backend topics
- InSPEC
 - Current pilot release 1.1/1.2/1.3 with many new features
 - Release 2.0 as stabilization planned for July
 - Open for application specific cooperations
 - Next topics
 - Line scanning (advanced strategies)
 - Integration with TRACER
 - Layout comparison/ more evaluation modules
 - Improved contour detection







Thank You!

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